

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/537,946	HAALAND, JAN FRODE	
Examiner		Art Unit		Page 1 of 1
TUYEN T. NGUYEN		2832		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0164844	07-2006	To, Ban Chin	362/382
*	B	US-6,565,230	05-2003	Ashley, Josh	362/650
*	C	US-6,420,350	07-2002	Fleischner, Albert M	514/62
*	D	US-5,664,869	09-1997	Bitton, Jacques	362/147
*	E	US-5,440,471	08-1995	Zadeh, Rohollah E.	362/365
*	F	US-4,459,648	07-1984	Ullman, Allan	362/307
*	G	US-3,683,173	08-1972	Edwin F. Guth, Jr.	362/366
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	42 08 660 A1	09-1993	DE	Halemeier	---
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.